TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC74HC390AP,TC74HC390AF,TC74HC390AFN

#### **Dual Decade Counter**

The TC74HC390A is a high speed CMOS DUAL DECADE COUNTER fabricated with silicon gate C<sup>2</sup>MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

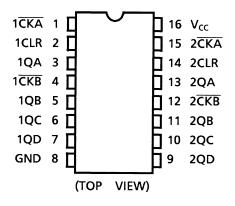
It consists of two independent 4-bit counters, each composed of a divide-by-two and a divide-by-five counter. The divide-by-two counter is incremented on the negative going transition of clock A  $(\overline{CKA})$ . The divided-by-five counter is incremented on the negative going transition of clock B  $(\overline{CKB})$ . The counter can be cascaded to form decade, bi-quinary, or various combinations up to a divide-by-100 counter. When the CLR input is set high, the Q outputs are set to low independent of the clock inputs.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

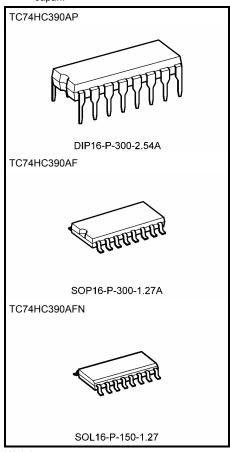
#### **Features**

- High speed:  $f_{max} = 84 \text{ MHz}$  (typ.) at  $V_{CC} = 5 \text{ V}$
- Low power dissipation:  $ICC = 4 \mu A \text{ (max)}$  at Ta = 25 °C
- High noise immunity: V<sub>NIH</sub> = V<sub>NIL</sub> = 28% V<sub>CC</sub> (min)
- · Output drive capability: 10 LSTTL loads
- Symmetrical output impedance: |IOH| = IOL = 4 mA (min)
- Balanced propagation delays:  $t_pLH \simeq t_pHL$
- Wide operating voltage range: V<sub>CC</sub> (opr) = 2~6 V
- Pin and function compatible with 74LS390

#### **Pin Assignment**



Note: xxxFN (JEDEC SOP) is not available in Japan.

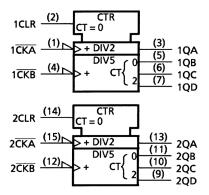


Weight

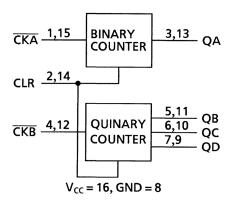
DIP16-P-300-2.54A : 1.00 g (typ.) SOP16-P-300-1.27A : 0.18 g (typ.) SOL16-P-150-1.27 : 0.13 g (typ.)

1 2007-10-01

# **IEC Logic Symbol**



# **Block Diagram**

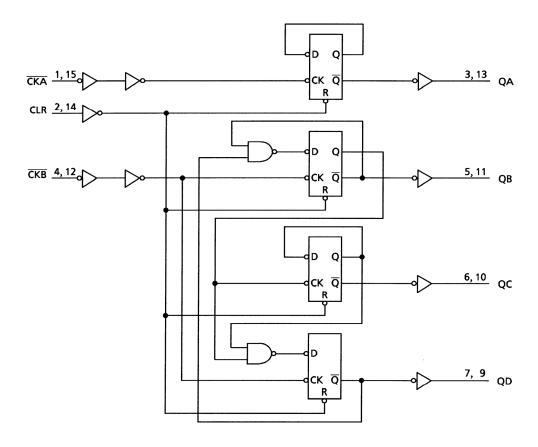


# **Truth Table**

	Inputs		Outputs						
CKA	CKB	CLR	QA	QB	QC	QD			
Х	Х	Н	L	L	L	L			
$\rightarrow$	Х	L	Binary Count Up						
Х	$\neg$	L	Quinary Count Up						

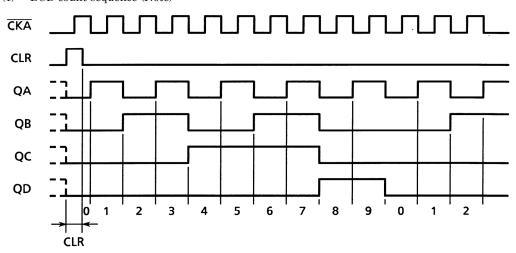
X: Don't care

# System Diagram (1/2 package)

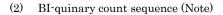


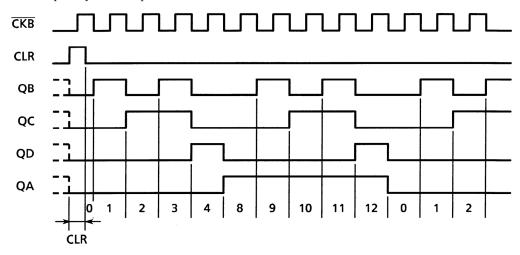
# **Timing Chart**

(1) BCD count sequence (Note)



Note: QA connected to  $\overline{\text{CKB}}$ 





Note: QD connected to CKA

### **Absolute Maximum Ratings (Note 1)**

Characteristics	Symbol	Rating	Unit
Supply voltage range	Vcc	-0.5~7	V
DC input voltage	V <sub>IN</sub>	-0.5~V <sub>CC</sub> + 0.5	V
DC output voltage	Vout	-0.5~V <sub>CC</sub> + 0.5	V
Input diode current	I <sub>IK</sub>	±20	mA
Output diode current	lok	±20	mA
DC output current	lout	±25	mA
DC V <sub>CC</sub> /ground current	Icc	±50	mA
Power dissipation	PD	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	T <sub>stg</sub>	-65~150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of Ta = -40 to 65°C. From Ta = 65 to 85°C a derating factor of -10 mW/°C shall be applied until 300 mW.

### **Operating Ranges (Note)**

Characteristics	Characteristics Symbol		Unit
Supply voltage	V <sub>CC</sub>	2~6	V
Input voltage	V <sub>IN</sub>	0~V <sub>CC</sub>	V
Output voltage	V <sub>OUT</sub>	0~V <sub>CC</sub>	V
Operating temperature	T <sub>opr</sub>	-40~85	°C
		0~1000 (V <sub>CC</sub> = 2.0 V)	
Input rise and fall time	t <sub>r</sub> , t <sub>f</sub>	0~500 (V <sub>CC</sub> = 4.5 V)	ns
		0~400 (V <sub>CC</sub> = 6.0 V)	

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

4



# **Electrical Characteristics**

### **DC Characteristics**

Characteristics	Symbol	Test Condition		-	Ta = 25°C			Ta = -40~85°C		
Characteristics				V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	Unit
				2.0	1.50	_	_	1.50	_	
High-level input voltage	$V_{IH}$		_	4.5	3.15	_		3.15	_	V
ŭ				6.0	4.20	_	_	4.20	_	
				2.0	_	_	0.50	_	0.50	
Low-level input voltage	$V_{IL}$	_		4.5	_	_	1.35	_	1.35	V
_				6.0	_	_	1.80	_	1.80	
	Vон	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>		2.0	1.9	2.0	_	1.9	_	
			$I_{OH} = -20~\mu A$	4.5	4.4	4.5	_	4.4	_	
High-level output voltage				6.0	5.9	6.0	_	5.9	_	V
			$I_{OH} = -4 \text{ mA}$	4.5	4.18	4.31	_	4.13	_	
			$I_{OH} = -5.2 \text{ mA}$	6.0	5.68	5.80		5.63	_	
	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>		2.0	_	0.0	0.1	_	0.1	
			$I_{OL}=20~\mu A$	4.5	_	0.0	0.1	_	0.1	
Low-level output voltage				6.0	_	0.0	0.1	_	0.1	V
			I <sub>OL</sub> = 4 mA	4.5	_	0.17	0.26	_	0.33	
			$I_{OL} = 5.2 \text{ mA}$	6.0	_	0.18	0.26	_	0.33	
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND		6.0		_	±0.1	_	±1.0	μА
Quiescent supply current	Icc	V <sub>IN</sub> = V <sub>CC</sub> or GND		6.0	_	_	4.0	_	40.0	μА

# Timing Requirements (input: $t_r = t_f = 6 \text{ ns}$ )

Characteristics	Symbol	Test Condition	Test Condition			Ta = −40 ~85°C	Unit
			V <sub>CC</sub> (V)	Тур.	Limit	Limit	
Minimum pulse width	<b>t</b> . a.n		2.0	_	75	95	
(CK)	t <sub>W (H)</sub>	_	4.5	_	15	19	ns
(CK)	t <sub>W (L)</sub>		6.0		13	16	
Minimum pulse width			2.0	_	75	95	
(CLR)	tw (H)	_	4.5	_	15	19	ns
(OLIV)			6.0		13	16	
	t <sub>rem</sub>		2.0		25	30	
Minimum removal time		_	4.5	_	5	6	ns
			6.0		5	5	
Clock frequency	f		2.0	_	6	5	
(CKA)		_	4.5	_	32	26	MHz
(CRA)			6.0	_	38	31	
Clock fraguency	f		2.0	_	6	5	
Clock frequency ( CKB )		_	4.5	_	31	25	MHz
(CND)			6.0		36	29	



# AC Characteristics (C<sub>L</sub> = 15 pF, $V_{CC}$ = 5 V, Ta = 25°C input: $t_r$ = $t_f$ = 6 ns)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Output transition time	t <sub>TLH</sub>	_	_	4	8	ns
	t <sub>THL</sub>					
Propagation delay time	t <sub>pLH</sub>	_		10	20	ns
(CKA -QA)	t <sub>pHL</sub>					
Propagation delay time	t <sub>pLH</sub>	QA connected to CKB	_	29	51	ns
(CKA -QC)	t <sub>pHL</sub>	and connected to one				113
Propagation delay time	t <sub>pLH</sub>			12	22	ns
( CKB -QB, QD)	t <sub>pHL</sub>	_		12	22	113
Propagation delay time	t <sub>pLH</sub>		_	17	32	ns
( CKB -QC)	t <sub>pHL</sub>	_				113
Propagation delay time	4			12	26	20
(CLR-Qn)	t <sub>pHL</sub>	_	_	12	20	ns
Maximum clock frequency			0.5	0.4		
(CKA)	f <sub>max</sub>	_	35	84	_	MHz
Maximum clock frequency	f		33	65		MHz
( CKB )	f <sub>max</sub>	_	33	05	_	IVI⊓Z



### AC Characteristics ( $C_L = 50 \text{ pF}$ , input: $t_r = t_f = 6 \text{ ns}$ )

Characteristics	Symbol	Test Condition		-	Га = 25°C	)	Ta = -40~85°C		Unit
Characteristics	Syllibol		V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	Oill
	4		2.0	_	30	75	_	95	
Output transition time	t <sub>TLH</sub>	_	4.5	_	8	15		19	ns
	tTHL		6.0	_	7	13	_	16	
Propagation delay	t <sub>pLH</sub>		2.0	_	39	120	_	150	
time	t <sub>pHL</sub>	_	4.5	_	13	24	_	30	ns
( CKA -QA)	φпь		6.0	_	11	20	_	26	
Propagation delay	t <sub>pLH</sub>		2.0	_	102	290	_	365	
time	t <sub>pHL</sub>	QA connected to CKB	4.5	_	34	58	_	73	ns
( CKA -QC)	ψп∟		6.0	_	29	49	_	62	
Propagation delay	t <sub>pLH</sub>		2.0	_	45	130	_	165	
time ——	t <sub>pHL</sub>	_	4.5	_	15	26	_	33	ns
(CKB-QB, QD)	фпь		6.0	_	13	22	_	28	
Propagation delay	t <sub>pLH</sub>		2.0	_	63	185	_	230	
time	t <sub>pHL</sub>	_	4.5	_	21	37		46	ns
( CKB -QC)	ψп∟		6.0	_	18	31	_	39	
Propagation delay			2.0	_	45	150	_	190	
time	$t_{pHL}$	_	4.5	_	15	30	_	38	ns
(CLR-Qn)			6.0	_	13	26	_	32	
Maximum clock			2.0	6	20	_	5	_	
frequency	f <sub>max</sub>	_	4.5	32	77	_	26	_	MHz
(CKA)			6.0	38	90	_	31	_	
Maximum clock			2.0	6	15	_	5	_	
frequency	f <sub>max</sub>	_	4.5	32	60	_	25	_	MHz
(CKB)			6.0	36	70	_	29	_	
Input capacitance	C <sub>IN</sub>	_		_	5	10	_	10	pF
Power dissipation	$C_{PD}$	_		_	44	_			pF
capacitance	(Note)								۳'

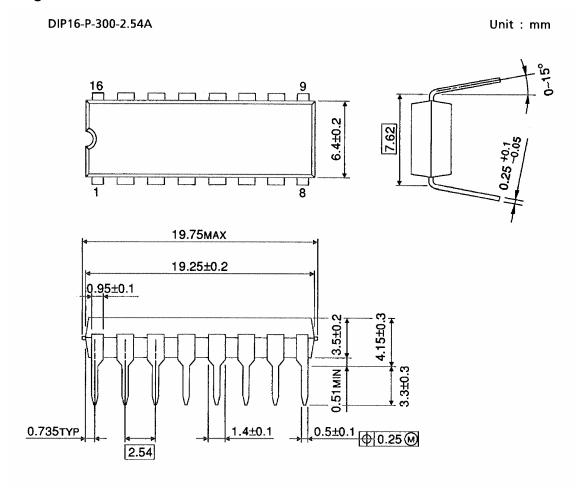
Note: CPD is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

 $I_{CC}$  (opr) =  $C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/2$  (per counter)



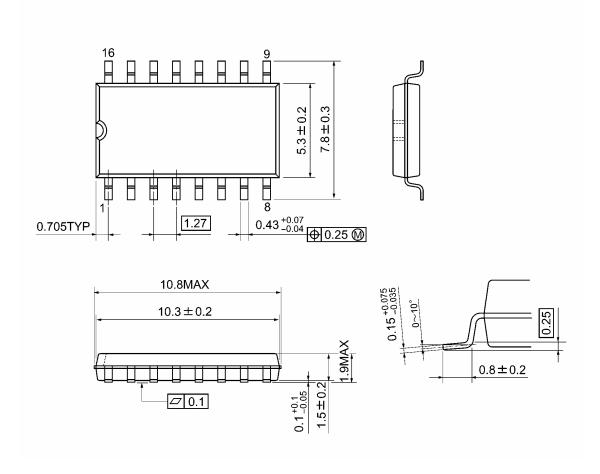
# **Package Dimensions**



Weight: 1.00 g (typ.)

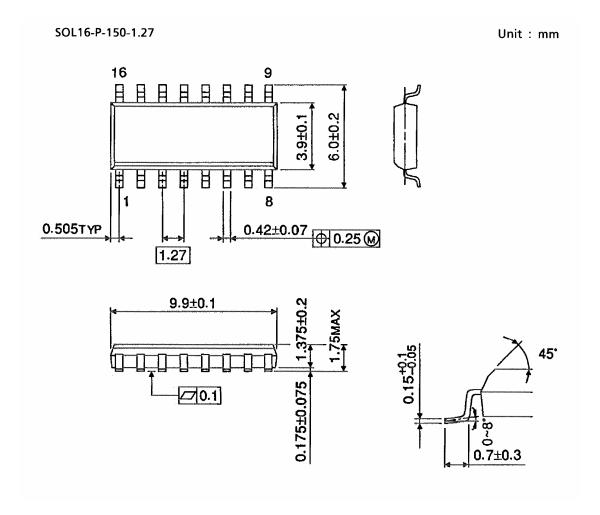
# **Package Dimensions**

SOP16-P-300-1.27A Unit: mm



Weight: 0.18 g (typ.)

# **Package Dimensions (Note)**



Note: This package is not available in Japan.

Weight: 0.13 g (typ.)

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20070701-EN GENERAL

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